

Notice of References Cited	Application/Control No. 10/615,885	Applicant(s)/Patent Under Reexamination DUAN ET AL.	
	Examiner DANIEL G. MARIAM	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,341,283	01-2002	Yamakawa et al.	707/5
*	B	US-6,728,706	04-2004	Aggarwal et al.	707/5
*	C	US-6,859,802	02-2005	Rui, Yong	707/5
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tusk, et al "Automated feature selection through relevance feedback", IEEE, pp. 3691-3693, 2/2003.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.